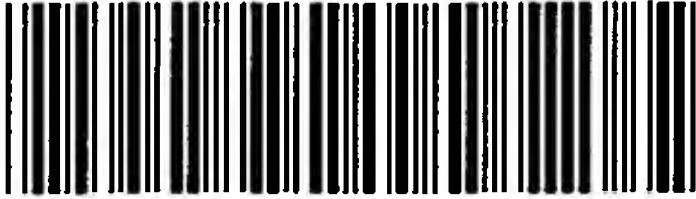


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/709,073	HSIEH, WEI-JIA	
	Examiner	Art Unit	
	Biju Chandran	2835	

SEARCHED			
Class	Subclass	Date	Examiner
361	695	11/25/2005	BIC

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
see search history		